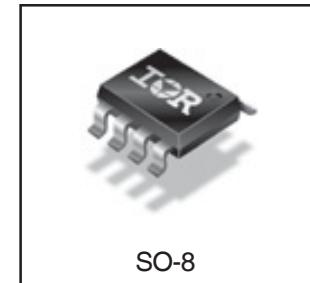
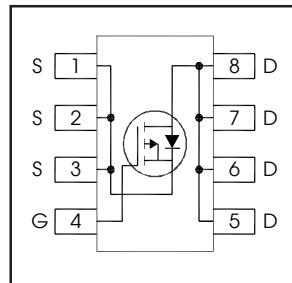


V_{DS}	-30	V
$R_{DS(on)}$ max (@$V_{GS} = -10V$)	4.6	$m\Omega$
$R_{DS(on)}$ max (@$V_{GS} = -4.5V$)	6.8	
Q_g (typical)	58	nC
I_D (@$T_A = 25^\circ C$)	-20	A



Features

- Industry-standard pinout SO-8 Package
- Compatible with Existing Surface Mount Techniques
- RoHS Compliant, Halogen-Free
- MSL1, Industrial qualification

Benefits

- Multi-Vendor Compatibility
- Easier Manufacturing
- Environmentally Friendlier
- Increased Reliability

Base Part Number	Package Type	Standard Pack		Orderable Part Number
		Form	Quantity	
IRF9310PbF-1	SO-8	Tube/Bulk	95	IRF9310PbF-1
		Tape and Reel	4000	IRF9310TRPbF-1

Absolute Maximum Ratings

	Parameter	Max.	Units
V_{DS}	Drain-to-Source Voltage	-30	V
V_{GS}	Gate-to-Source Voltage	± 20	
$I_D @ T_A = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	-20	
$I_D @ T_A = 70^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	-16	A
I_{DM}	Pulsed Drain Current ①	-160	
$P_D @ T_A = 25^\circ C$	Power Dissipation ④	2.5	W
$P_D @ T_A = 70^\circ C$	Power Dissipation ④	1.6	
	Linear Derating Factor	0.02	W/ $^\circ C$
T_J	Operating Junction and Storage Temperature Range	-55 to +150	$^\circ C$
T_{STG}			

Notes ① through ⑤ are on page 2

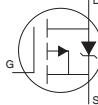
Static @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	-30	—	—	V	$V_{\text{GS}} = 0\text{V}, I_D = -250\mu\text{A}$
$\Delta \text{BV}_{\text{DSS}/\Delta T_J}$	Breakdown Voltage Temp. Coefficient	—	0.020	—	$\text{V}/^\circ\text{C}$	Reference to 25°C , $I_D = -1\text{mA}$
$R_{\text{DS(on)}}$	Static Drain-to-Source On-Resistance	—	3.9	4.6	$\text{m}\Omega$	$V_{\text{GS}} = -10\text{V}, I_D = -20\text{A}$ ③
		—	5.8	6.8		$V_{\text{GS}} = -4.5\text{V}, I_D = -16\text{A}$ ③
$V_{\text{GS(th)}}$	Gate Threshold Voltage	-1.3	-1.8	-2.4	V	$V_{\text{DS}} = V_{\text{GS}}, I_D = -100\mu\text{A}$
$\Delta V_{\text{GS(th)}}$	Gate Threshold Voltage Coefficient	—	-5.8	—	$\text{mV}/^\circ\text{C}$	
I_{DSS}	Drain-to-Source Leakage Current	—	—	-1.0	μA	$V_{\text{DS}} = -24\text{V}, V_{\text{GS}} = 0\text{V}$
		—	—	-150	—	$V_{\text{DS}} = -24\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 125^\circ\text{C}$
I_{GSS}	Gate-to-Source Forward Leakage	—	—	-100	nA	$V_{\text{GS}} = -20\text{V}$
	Gate-to-Source Reverse Leakage	—	—	100	—	$V_{\text{GS}} = 20\text{V}$
g_{fs}	Forward Transconductance	39	—	—	S	$V_{\text{DS}} = -10\text{V}, I_D = -16\text{A}$
Q_g	Total Gate Charge ⑥	—	58	—	nC	$V_{\text{DS}} = -15\text{V}, V_{\text{GS}} = -4.5\text{V}, I_D = -16\text{A}$
Q_g	Total Gate Charge ⑥	—	110	165	nC	$V_{\text{GS}} = -10\text{V}$
Q_{gs}	Gate-to-Source Charge ⑥	—	17	—	nC	$V_{\text{DS}} = -15\text{V}$
Q_{gd}	Gate-to-Drain Charge ⑥	—	28	—	nC	$I_D = -16\text{A}$
R_G	Gate Resistance ⑥	—	2.8	—	Ω	—
$t_{\text{d(on)}}$	Turn-On Delay Time	—	25	—	ns	$V_{\text{DD}} = -15\text{V}, V_{\text{GS}} = -4.5\text{V}$ ③
t_r	Rise Time	—	47	—		$I_D = -1.0\text{A}$
$t_{\text{d(off)}}$	Turn-Off Delay Time	—	65	—		$R_G = 1.8\Omega$
t_f	Fall Time	—	70	—		See Figs. 20a &20b
C_{iss}	Input Capacitance	—	5250	—	pF	$V_{\text{GS}} = 0\text{V}$
C_{oss}	Output Capacitance	—	1300	—		$V_{\text{DS}} = -15\text{V}$
C_{rss}	Reverse Transfer Capacitance	—	880	—		$f = 1.0\text{MHz}$

Avalanche Characteristics

	Parameter	Typ.	Max.	Units
E_{AS}	Single Pulse Avalanche Energy ②	—	630	mJ
I_{AR}	Avalanche Current ①	—	-16	A

Diode Characteristics

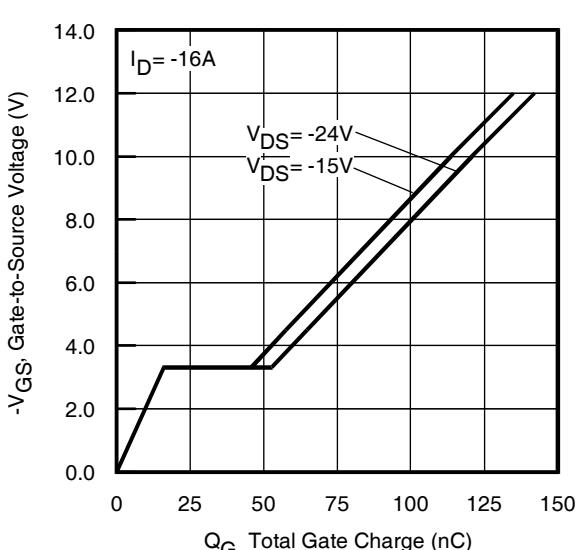
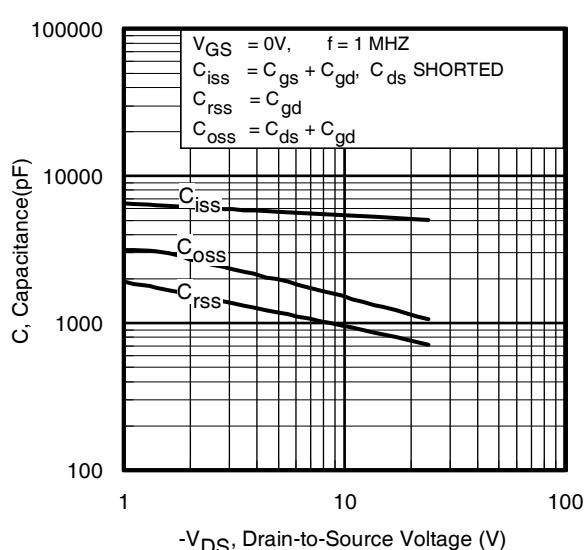
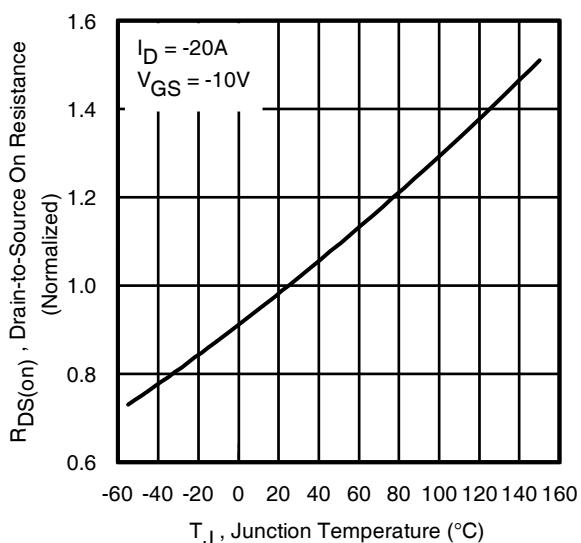
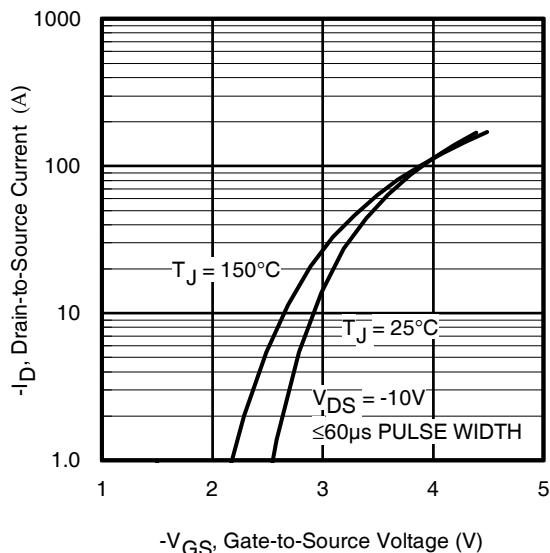
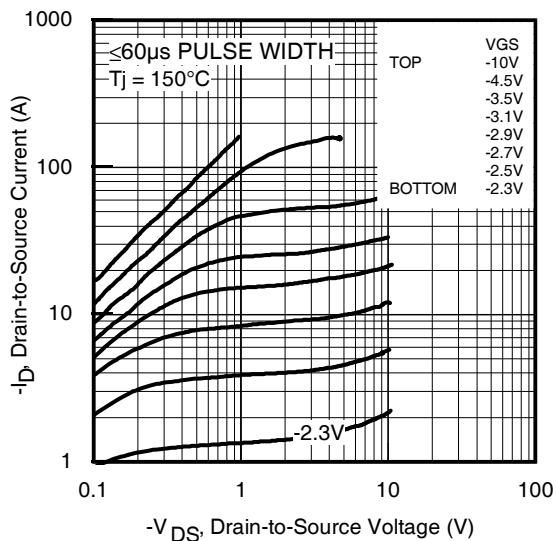
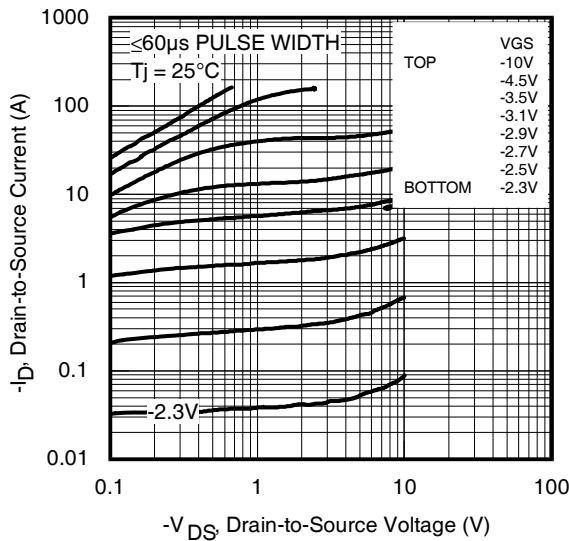
	Parameter	Min.	Typ.	Max.	Units	Conditions
I_S	Continuous Source Current (Body Diode)	—	—	-2.5	A	MOSFET symbol showing the integral reverse p-n junction diode.
I_{SM}	Pulsed Source Current (Body Diode) ①	—	—	-160		
V_{SD}	Diode Forward Voltage	—	—	-1.2	V	$T_J = 25^\circ\text{C}, I_S = -2.5\text{A}, V_{\text{GS}} = 0\text{V}$ ③
t_{rr}	Reverse Recovery Time	—	71	107	ns	$T_J = 25^\circ\text{C}, I_F = -2.5\text{A}, V_{\text{DD}} = -24\text{V}$
Q_{rr}	Reverse Recovery Charge	—	12	18	nC	$dI/dt = 100\text{A}/\mu\text{s}$ ③

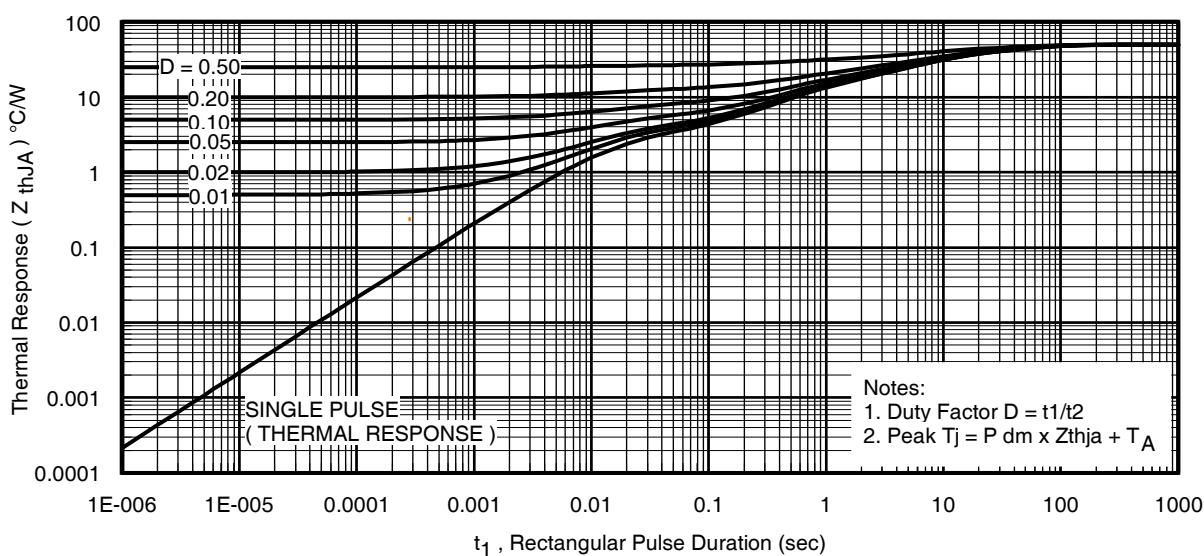
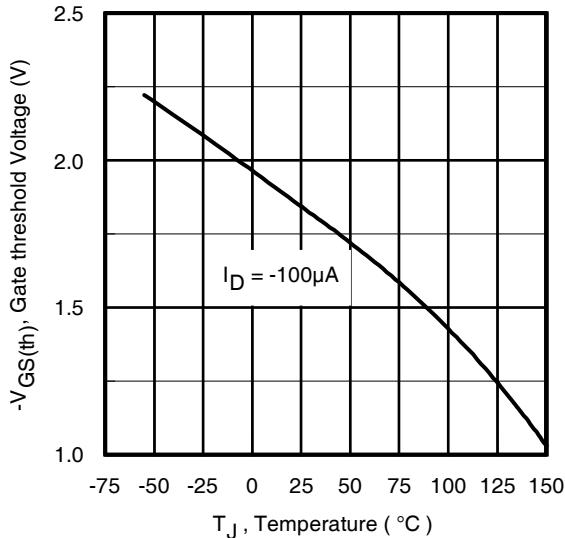
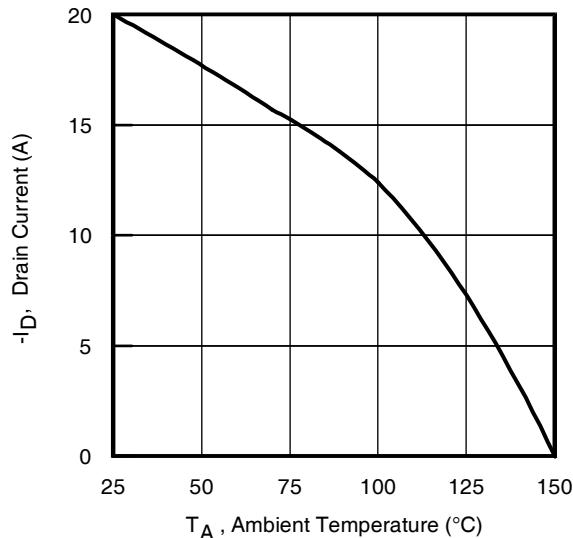
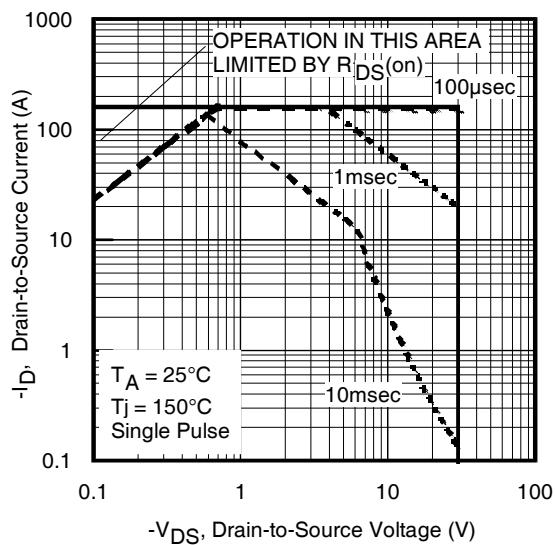
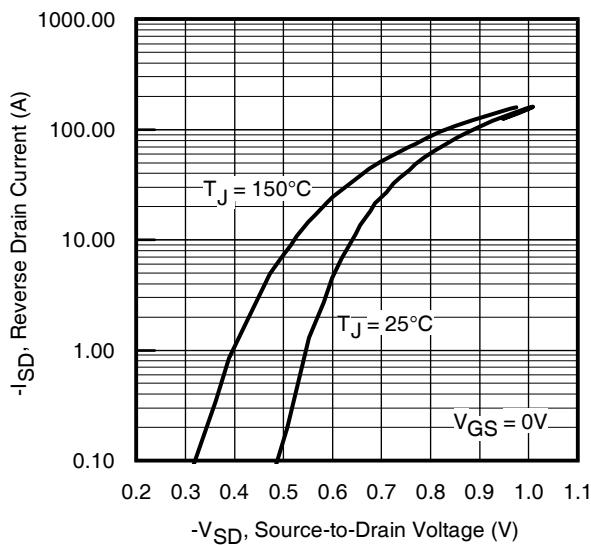
Thermal Resistance

	Parameter	Typ.	Max.	Units
$R_{\theta\text{JL}}$	Junction-to-Drain Lead ⑤	—	20	$^\circ\text{C}/\text{W}$
$R_{\theta\text{JA}}$	Junction-to-Ambient ④	—	50	

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature.
- ② Starting $T_J = 25^\circ\text{C}$, $L = 4.9\text{mH}$, $R_G = 25\Omega$, $I_{\text{AS}} = -16\text{A}$.
- ③ Pulse width $\leq 400\mu\text{s}$; duty cycle $\leq 2\%$.
- ④ When mounted on 1 inch square copper board.
- ⑤ R_θ is measured at T_J of approximately 90°C .
- ⑥ For DESIGN AID ONLY, not subject to production testing.





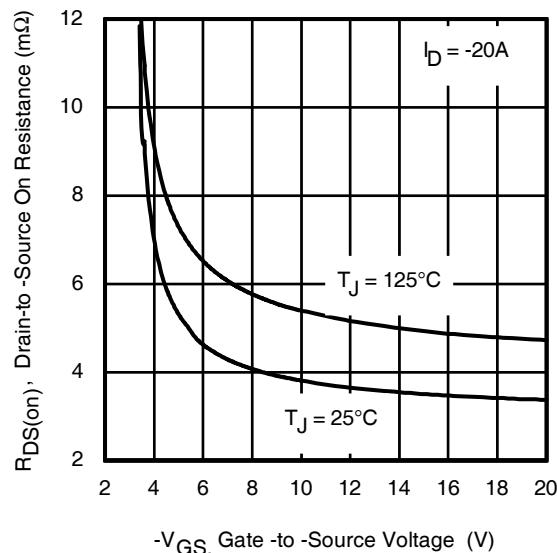


Fig 12. On-Resistance vs. Gate Voltage

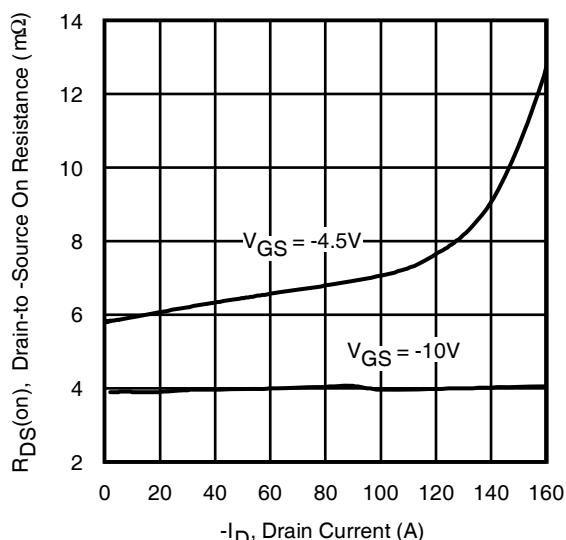


Fig 13. Typical On-Resistance vs. Drain Current

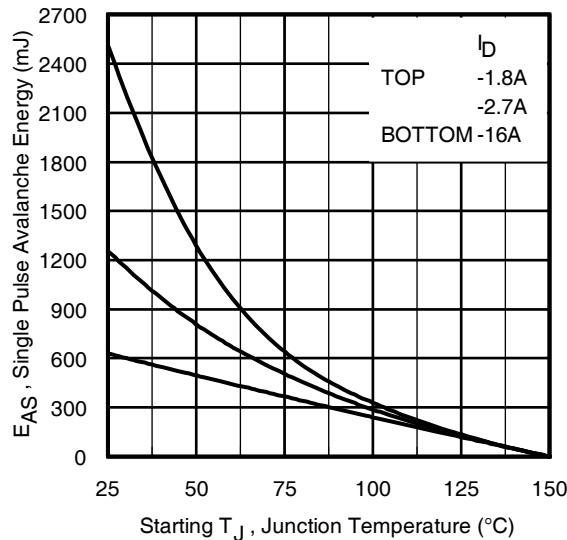


Fig 14. Maximum Avalanche Energy vs. Drain Current

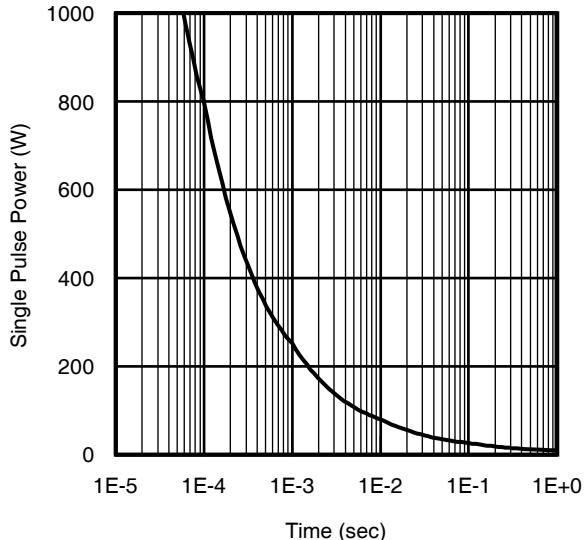


Fig 16. Typical Power vs. Time

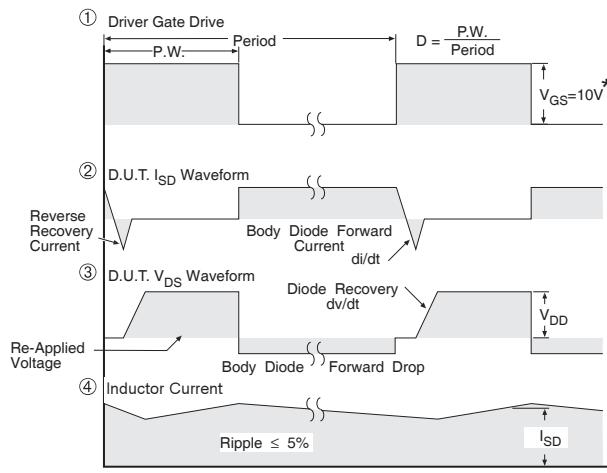
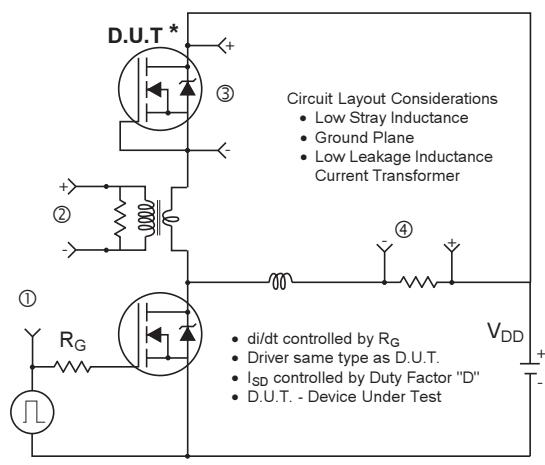
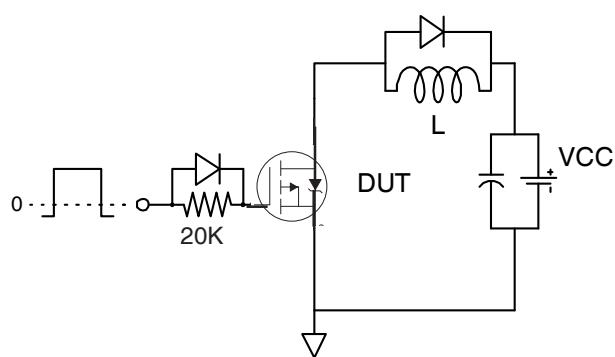
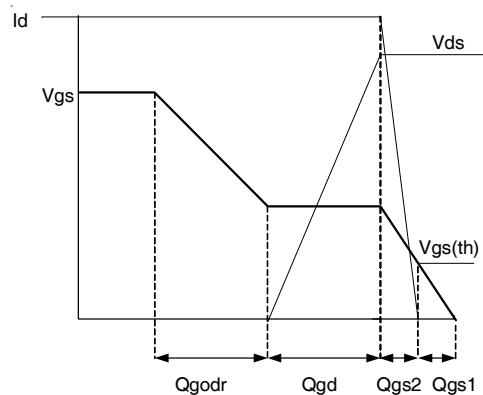
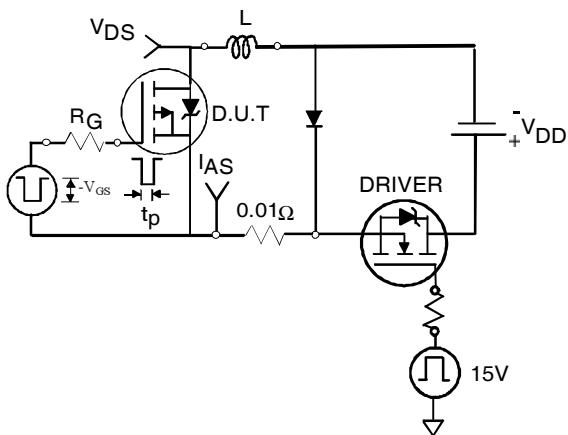
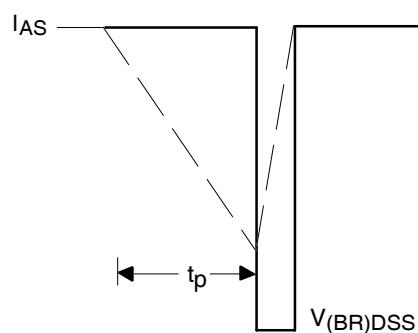
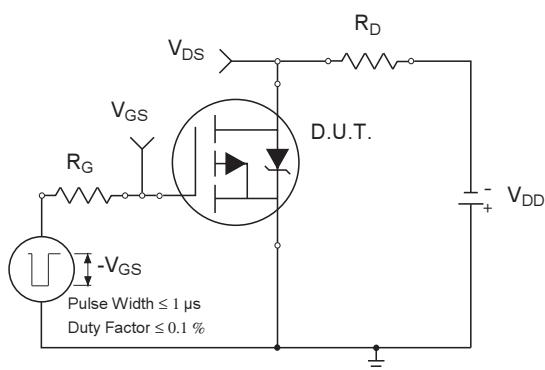
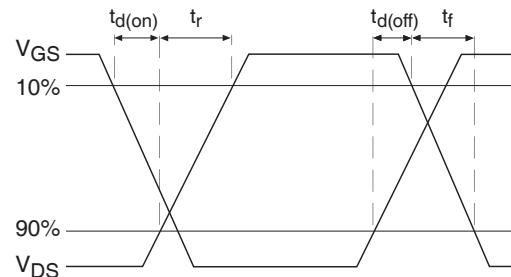
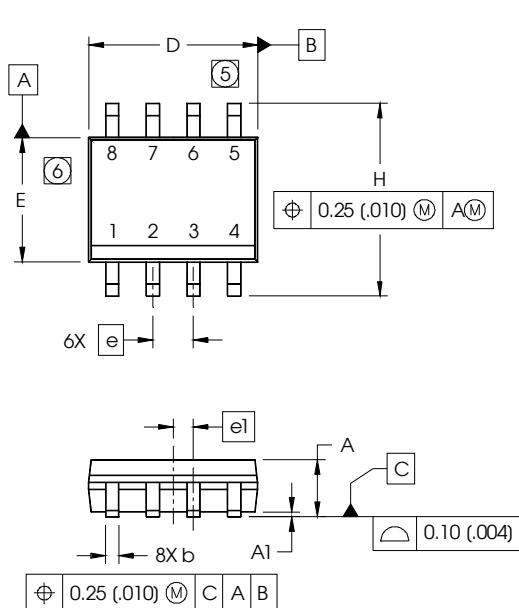


Fig 17. Diode Reverse Recovery Test Circuit for P-Channel HEXFET® Power MOSFETs

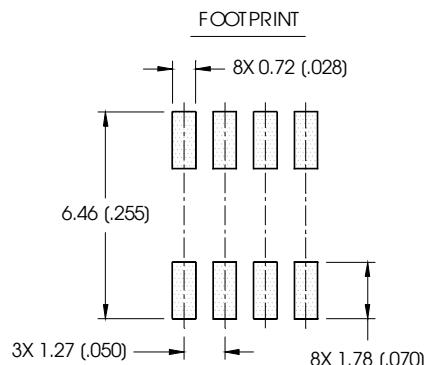
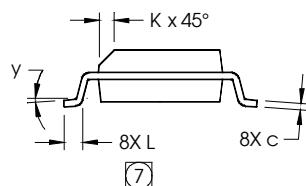
**Fig 18a.** Gate Charge Test Circuit**Fig 18b.** Gate Charge Waveform**Fig 19a.** Unclamped Inductive Test Circuit**Fig 19b.** Unclamped Inductive Waveforms**Fig 20a.** Switching Time Test Circuit**Fig 20b.** Switching Time Waveforms

SO-8 Package Outline (Mosfet & Fetky)

Dimensions are shown in millimeters (inches)



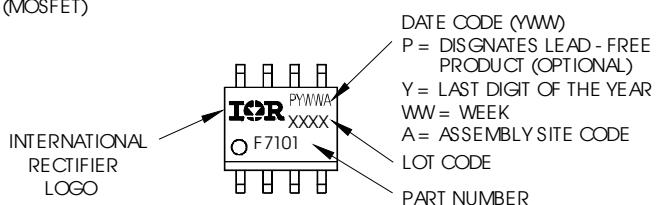
DIM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	.0532	.0688	1.35	1.75
A1	.0040	.0098	0.10	0.25
b	.013	.020	0.33	0.51
c	.0075	.0098	0.19	0.25
D	.189	.1968	4.80	5.00
E	.1497	.1574	3.80	4.00
e	.050	BASIC	1.27	BASIC
e1	.025	BASIC	0.635	BASIC
H	.2284	.2440	5.80	6.20
K	.0099	.0196	0.25	0.50
L	.016	.050	0.40	1.27
y	0°	8°	0°	8°



- NOTES:
1. DIMENSIONING & TOLERANCING PER ASME Y14.5M-1994.
 2. CONTROLLING DIMENSION: MILLIMETER
 3. DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).
 4. OUTLINE CONFORMS TO JEDEC OUTLINE MS-012AA.
 5. DIMENSION DOES NOT INCLUDE MOLD PROTRUSIONS.
MOLD PROTRUSIONS NOT TO EXCEED 0.15 (.006).
 6. DIMENSION DOES NOT INCLUDE MOLD PROTRUSIONS.
MOLD PROTRUSIONS NOT TO EXCEED 0.25 (.010).
 7. DIMENSION IS THE LENGTH OF LEAD FOR SOLDERING TO
A SUBSTRATE.

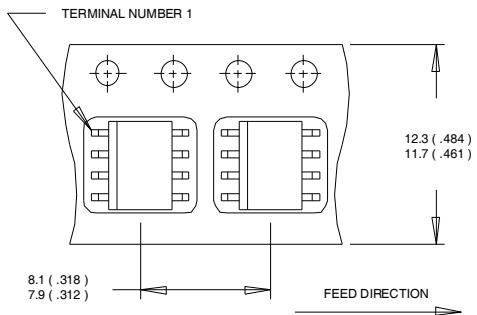
SO-8 Part Marking Information

EXAMPLE: THIS IS AN IRF7101 (MOSFET)

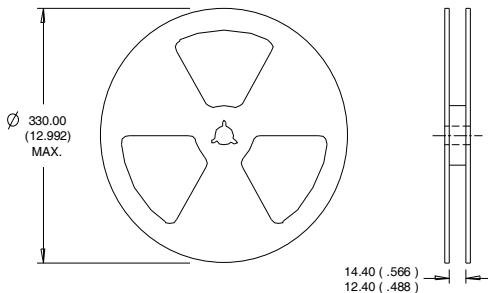


Note: For the most current drawing please refer to IR website at: <http://www.irf.com/package/>

SO-8 Tape and Reel (Dimensions are shown in millimeters (inches))



NOTES:
 1. CONTROLLING DIMENSION : MILLIMETER.
 2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS(INCHES).
 3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



NOTES :
 1. CONTROLLING DIMENSION : MILLIMETER.
 2. OUTLINE CONFORMS TO EIA-481 & EIA-541.

Note: For the most current drawing please refer to IR website at: <http://www.irf.com/package/>

Qualification information[†]

Qualification level	Industrial (per JEDEC JESD47F ^{††} guidelines)	
Moisture Sensitivity Level	SO-8	MSL1 (per JEDEC J-STD-020D ^{††})
RoHS compliant	Yes	

[†] Qualification standards can be found at International Rectifier's web site: <http://www.irf.com/product-info/reliability>

^{††} Applicable version of JEDEC standard at the time of product release

International
IR Rectifier

IR WORLD HEADQUARTERS: 101 N. Sepulveda Blvd., El Segundo, California 90245, USA
 To contact International Rectifier, please visit <http://www.irf.com/whoto-call/>